

ON Semiconductor®

# FGB40T65SPD-F085 650V, 40A Field Stop Trench IGBT

#### **Features**

- · AEC-Q101 Qualified
- Low Saturation Voltage: V<sub>CE(sat)</sub> = 2.0 V(Typ.) @ I<sub>C</sub> = 40 A
- 100% of the parts are dynamically tested (Note 1)
- Short Circuit Ruggedness > 5 μs @ 25 °C
- Maximum Junction Temperature : T<sub>J</sub> = 175 °C
- · Fast Switching
- Tight Parameter Distribution
- · Positive Temperature Coefficient for Easy Parallel Operation
- · Copacked with soft, fast recovery diode
- · RoHS Compliant

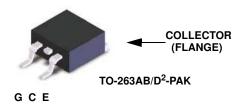


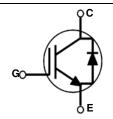
## **General Description**

Using the novel field stop 3rd generation IGBT technology, FGH40T65SPD-F085 offers the optimum performance with both low conduction loss and switching loss for a high efficiency operation in various applications, while provides 50V higher blocking voltage and rugged high current switching reliability. Meanwhile, this part also offers and advantage of outstanding performance in parallel operation.

## **Applications**

- · Onboard Charger
- · AirCon Compressor
- PTC Heater
- Motor Drivers
- Other automotive power-train and auxiliary applications





# **Absolute Maximum Ratings**

Symbol	Description		Ratings	Units	
V <sub>CES</sub>	Collector to Emitter Voltage		650	V	
V <sub>GES</sub>	Gate to Emitter Voltage		± 20	V	
	Transient Gate to Emitter Voltage		± 30	V	
l <sub>o</sub>	Collector Current	@ T <sub>C</sub> = 25 °C	80	Α	
l <sub>C</sub>	Collector Current	@ T <sub>C</sub> = 100 °C	40	Α	
I <sub>CM</sub>	Pulsed Collector Current	(Note 2)	120	Α	
I <sub>F</sub>	Diode Forward Current	@ T <sub>C</sub> = 25 °C	40	Α	
	Diode Forward Current	@ T <sub>C</sub> = 100 °C	20	Α	
I <sub>FM</sub>	Pulsed Diode Maximum Forward Current	t (Note 2)	120	Α	
P <sub>D</sub>	Maximum Power Dissipation	@ T <sub>C</sub> = 25 °C	267	W	
	Maximum Power Dissipation	@ T <sub>C</sub> = 100 °C	134	W	
SCWT	Short Circuit Withstand Time	@ T <sub>C</sub> = 25 °C	5	μS	
T <sub>J</sub>	Operating Junction Temperature		-55 to +175	°C	
T <sub>stg</sub>	Storage Temperature Range		-55 to +175	°C	
T <sub>L</sub>	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C	

- 1: Vcc = 400 V, VgE = 15 V, Ic = 120 A, Rg = 20  $\Omega$ , Inductive Load 2: Repetitive rating: pulse width limited by max. junction temperature

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Qty per Reel
FGB40T65SPD	FGB40T65SPD-F085	TO-263AB/D2-PAK	-	-	800ea

# Electrical Characteristics of the IGBT $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	teristics					
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 1mA	650	-	-	V
$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	Temperature Coefficient of Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 1mA	-	0.6	-	V/°C
I <sub>CES</sub>	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$	-	-	250	μΑ
I <sub>GES</sub>	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$	-	-	± 400	nA
On Charac	teristics					
V <sub>GE(th)</sub>	G-E Threshold Voltage	$I_C$ = 40mA, $V_{CE}$ = $V_{GE}$	4.0	5.8	7.5	V
		I <sub>C</sub> = 40A, V <sub>GE</sub> = 15V	-	2.0	2.4	V
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage	I <sub>C</sub> = 40A, V <sub>GE</sub> = 15V, T <sub>C</sub> = 175 °C	-	2.9	-	V
Dynamic C	haracteristics		•			
C <sub>ies</sub>	Input Capacitance		-	1520	-	pF
C <sub>oes</sub>	Output Capacitance	V <sub>CE</sub> = 30V <sub>,</sub> V <sub>GE</sub> = 0V, f = 1MHz	-	92	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance	I = IIVIDZ	-	15	-	pF
	Characteristics		•		•	
T <sub>d(on)</sub>	Turn-On Delay Time		-	18	-	ns
T <sub>r</sub>	Rise Time		-	26	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time	$V_{CC} = 400V, I_{C} = 40A,$	-	35	-	ns
T <sub>f</sub>	Fall Time	$R_G = 6\Omega, V_{GF} = 15V,$	-	10	-	ns
E <sub>on</sub>	Turn-On Switching Loss	Inductive Load, T <sub>C</sub> = 25 °C	-	0.97	-	mJ
E <sub>off</sub>	Turn-Off Switching Loss		-	0.28	-	mJ
E <sub>ts</sub>	Total Switching Loss		-	1.25	-	mJ
T <sub>d(on)</sub>	Turn-On Delay Time		-	14	-	ns
T <sub>r</sub>	Rise Time		-	35	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time	$V_{CC}$ = 400V, $I_{C}$ = 40A, $R_{G}$ = 6 $\Omega$ , $V_{GE}$ = 15V, Inductive Load, $T_{C}$ = 175 $^{o}$ C	-	38	-	ns
T <sub>f</sub>	Fall Time		-	13	-	ns
E <sub>on</sub>	Turn-On Switching Loss		-	1.61	-	mJ
E <sub>off</sub>	Turn-Off Switching Loss		-	0.47	-	mJ
E <sub>ts</sub>	Total Switching Loss		-	2.08	-	mJ
T <sub>SC</sub>	Short Circuit Withstand Time	$V_{CC} = 400V, V_{GE} = 15V,$ $R_{G} = 10\Omega$	5	-	-	μS

# **Electrical Characteristics of the IGBT** (Continued)

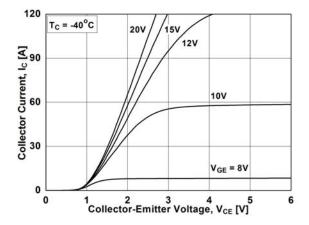
Symbol	Parameter	Test Conditions	Min.	Тур.	Max	Units
$Q_g$	Total Gate Charge	V <sub>CE</sub> = 400V, I <sub>C</sub> = 40A, V <sub>GE</sub> = 15V	-	36	-	nC
Q <sub>ge</sub>	Gate to Emitter Charge		-	12	-	nC
$Q_{gc}$	Gate to Collector Charge		-	11	1	nC

# Electrical Characteristics of the Diode T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max	Units
V <sub>FM</sub>	Diode Forward Voltage	I <sub>F</sub> = 20A	T <sub>C</sub> = 25 °C	-	2.0	2.7	V
			T <sub>C</sub> = 175 °C	-	1.8	-	
E <sub>rec</sub>	Reverse Recovery Energy	I <sub>F</sub> = 20A, dI <sub>F</sub> /dt = 200A/μs	T <sub>C</sub> = 175 °C	-	51	-	μJ
T <sub>rr</sub>	Diode Reverse Recovery Time		T <sub>C</sub> = 25 °C	-	34	-	ns
'rr			T <sub>C</sub> = 175 °C	-	206	-	110
Q <sub>rr</sub>	Diode Reverse Recovery Charge		T <sub>C</sub> = 25 °C	-	56	-	nC
α <sub>rr</sub>			T <sub>C</sub> = 175 °C	-	731	-	110

# **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction to Case	-	0.56	°C/W
$R_{\theta JC}(Diode)$	Thermal Resistance, Junction to Case	-	1.71	°C/W
$R_{\theta,JA}$	Thermal Resistance, Junction to Ambient	-	40	°C/W



**Figure 1. Typical Output Characteristics** 

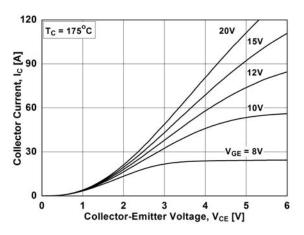


Figure 3. Typical Output Characteristics

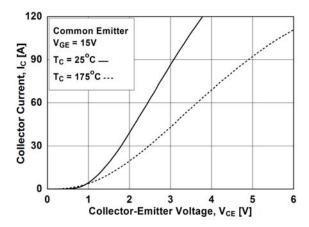
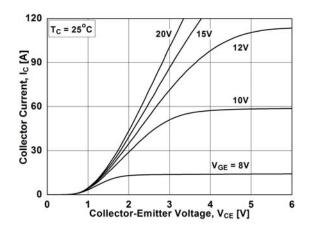


Figure 5. Typical Saturation Voltage



**Figure 2. Typical Output Characteristics** 

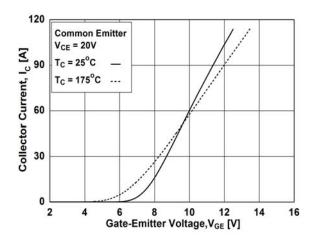


Figure 4. Transfer Characteristic

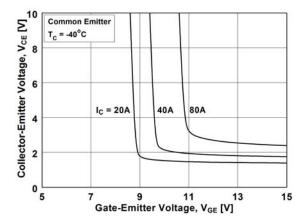


Figure 6. Saturation Voltage vs. V<sub>GE</sub> Characteristics

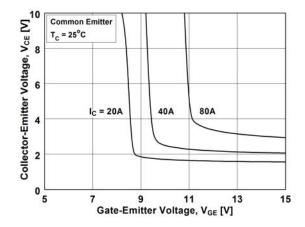


Figure 7. Saturation Voltage vs. V<sub>GE</sub>

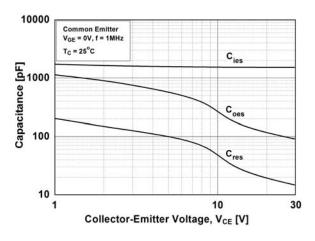


Figure 9. Capacitance Characteristics

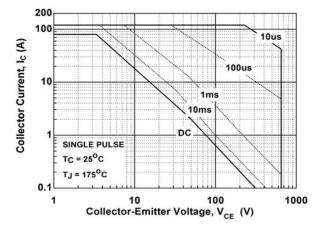


Figure 11. SOA Characteristics

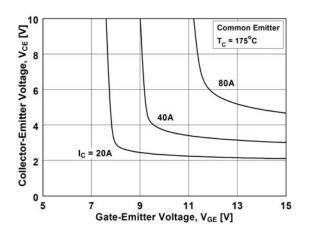


Figure 8. Saturation Voltage vs. V<sub>GE</sub>

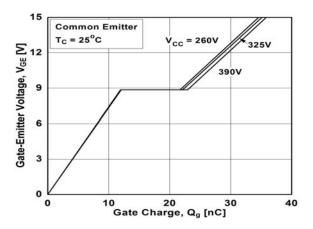


Figure 10. Gate charge Characteristics

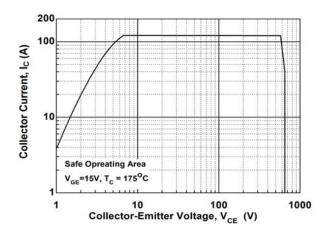


Figure 12. Turn off Switching SOA Characteristics

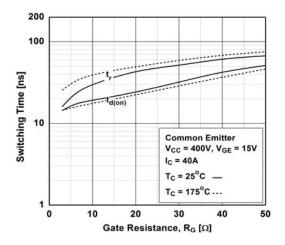


Figure 13. Turn-on Characteristics vs.
Gate Resistance

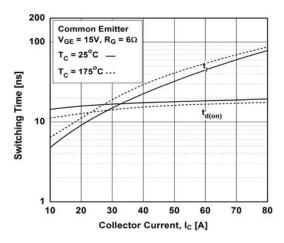


Figure 15. Turn-on Characteristics vs. Collector Current

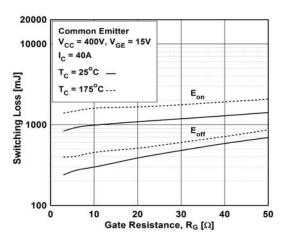


Figure 17. Switching Loss vs Gate Resistance

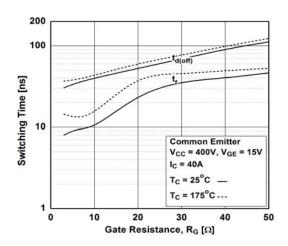


Figure 14. Turn-off Characteristics vs.
Gate Resistance

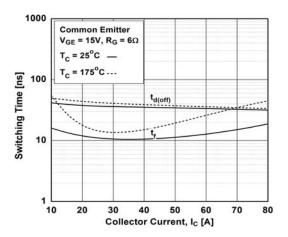


Figure 16. Turn-off Characteristics vs. Collector Current

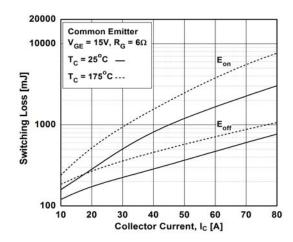


Figure 18. Switching Loss vs Collector Current

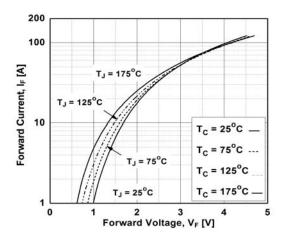


Figure 19. Forward Characteristics

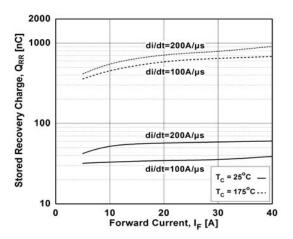


Figure 21. Stored Charge

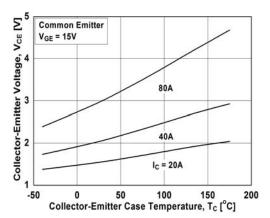


Figure 23. Saturation Voltage vs. Case Temperature at Variant Current Level

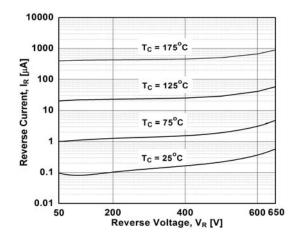


Figure 20. Reverse Current

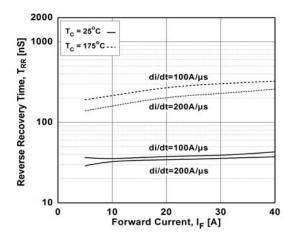


Figure 22. Reverse Recovery Time

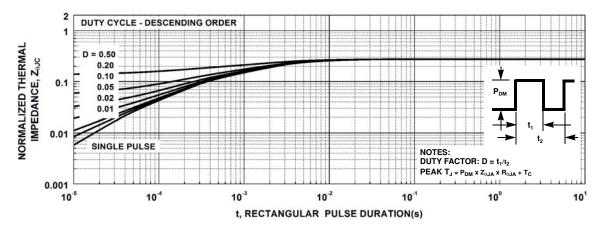


Figure 24. Transient Thermal Impedance of IGBT

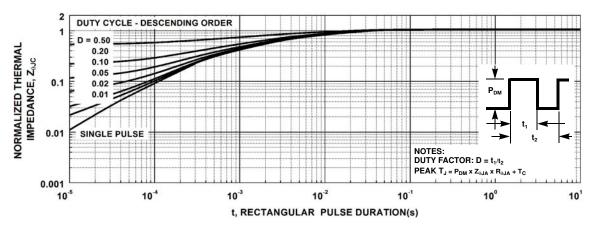


Figure 25. Transient Thermal Impedance of Diode

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